

NEW PRODUCT NEWS



BEAM CURRENT MONITOR

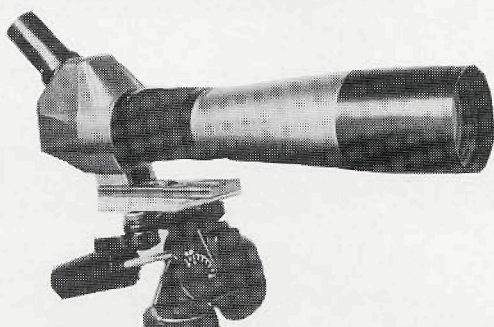
E. Fjeld Co., Inc. introduces a fast, effective method to monitor and maintain delivered beam current for specific scientific analysis. A self-contained, autoranging **Beam Current Monitor** allows the operator to monitor single-digit picoamps or hundreds of nanoamps. The easy-to-read LCD device installs quickly and consumes only 3 x 7 inches of operational space.

In addition, the Beam Current Monitor has been designed for ease of operation. Simply direct the electron beam into a Faraday Cup and power the Beam Current Monitor. The display will automatically illuminate the 3-digit LCD display. Autoranging begins immediately, precisely adjusting to the existing input current levels. The input range is 0 to -200 nA.

Ideal for EDS/WDS analysis or any operation requiring control and/or repetition of delivered beam current. Faraday attachments and elemental standards are available to complete the **Beam Current Monitor** package. PRICED @ \$985.00

E. Fjeld Co., Inc., 3 Executive Park Drive, N. Billerica, MA 01862
(508)667-1416 - Fax: (508)667-9059
Circle Reader Inquiry #40

LONG WORKING DISTANCE MICROSCOPE



MACROSCOPE LWD

A unique horizontal viewing long working distance microscope that provides magnification of 7X to 27X at a distance of about 500 mm. The unit is camera and video adaptable. MACROSCOPE LWD is available at greatly discounted closeout pricing (approximately \$1000 for basic unit and eyepiece).

For further details contact:

RF Inter-Science Company, PO Box 445, Coram, NY 11727
(516)698-4799, Fax: (516)698-4988, eMail: RFINTER@

Circle Reader Inquiry #41

EasyEDS

NORAN Instruments announces EasyEDS, a new approach for acquiring and displaying an image, spectra, maps, and linescans on the VOYAGER microanalysis and imaging system for SEM and TEM applications. EasyEDS combines the best of the VOYAGER system's spectral and image analysis technology with the latest, most efficient desktop. EasyEDS has a dual display for a reference image with indexed points and associated spectra. QuickClick buttons in the window let you automatically analyze samples with a single mouse click. The latest VOYAGER software also incorporates new tools for peak identification, annotation of spectra and images, and removable disks (JAZ and magneto-optical).

The IbeX application-specific and APeX full-spectrometers are recent additions to NORAN Instrument's wavelength-dispersive spectroscopy products, which include software options.

For additional information, contact NORAN Instruments at telephone: (608)831-6511 or Fax: (608)836-7224

Circle Reader Inquiry #42

New Calibrator for Nanoscope®
Scanning Probe Microscopes

Advanced Surface Microscopy and MOXTEK have announced a new calibration kit for Digital Instrument's Nanoscope® line of scanning probe microscopes.

With the SPM CALIBRATOR, users can:

- Quickly check dimensional measurements.
- Perform periodic calibration and performance checks of the microscope.
- Obtain nanometer-scale dimensional accuracy for the first time.
- Locate features with extraordinary precision (to 1/30th pixel).
- Accurately determine lateral dimensions from 10 nm to 20 micrometer with one standard.
- Analyze images for distortion and nonlinearity and check adjustments made to minimize distortion.

The SPM CALIBRATOR consists of an innovative, new reference standard and a special software package for data analysis and instrument recalibration. The reference standard consists of a highly regular, accurate, repetitive line-space pattern with nominal 300 nm period. Its exceptional uniformity speeds use by allowing measurements at random locations.

Designed as an enhancement to your microscope's standard software, the data analysis routines provide a fast, objective analysis. The feature locator has extraordinary precision (to 1/30th pixel). Critical dimension measurements will be even more accurate than before.

Dimensional accuracy is particularly important for industries such as:

- Electronics, where microlithography requires ever tighter tolerances; and
- Data storage, where mastering of compact discs depends on controlling pit geometry and spacing.

For further information, contact Advanced Surface Microscopy (317-251-1364, fax: 317-254-8690) or Moxtek (801-225-0930, Fax: 801-221-1121).

Circle Reader Inquiry #43

USED EQUIPMENT FOR SALE

☛ **TWO TEMS:** 1) Philips EM300 with goniometer and complete HNU EDS system. 2) Philips EM300RG with goniometer and complete EDAX 9800 EDS system, under current service contract. Each with many accessories - call for list. Best offer. Industrial Testing Laboratories: (314)771-7111.

☛ **Gatan Model 607/666 PEELS for Philips microscope.** \$5,000 or best offer. Contact Jim Jowe at (804)982-5646 or email: jh9s@virginia.edu

☛ **OLYMPUS MICROSCOPES** - all with 4 objs. - ALL LIKE NEW! 1) BX-50 (100w): \$5800, 2) BX-40 (30w): \$4500, 3) BHS (100w) Research: \$4800 - all are adaptable to a Photo Tri-Noc and 4) PM-10 Photomicrography System: \$3900. MICROGENICS: (707)277-7909

☛ **MILITARY RESEARCH LAB IS CLOSING** - Military contractor is selling at drastically reduced prices its Reichart Polycut S motorized sliding microtome, refrigerated and rotary microtomes, Sorvall ultramicrotome, Gatan Model 600 dual ion mill. Fisher embedding center, stereo microscopes, Perkin Elmer microdensitometer and LECO sulfur analyzer. For specification sheets, call: (202)544-0836.

☛ **Peak Instruments System 10 Wavelength Dispersive X-ray Analysis System.** Configured for B, C, O/F and S. Interfaces to ISI 100-B. Asking: \$7,500. Call John at (203)639-1338.